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(12) United States Design Patent

Treibergs et al.

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(54) **COMPLIANT GROUND BLOCK AND TESTING SYSTEM FOR TESTING INTEGRATED CIRCUITS**

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(**) Term: **15 Years**

(21) Appl. No.: **29/766,911**

(22) Filed: **Jan. 19, 2021**

(51) **LOC (14) Cl.** **13-03**

(52) **U.S. Cl.**
USPC **D13/182**

(58) **Field of Classification Search**
USPC D13/117, 121, 133, 164, 173, 182, 184, D13/199
CPC H05K 3/36; H05K 3/361; H05K 3/363; H05K 3/365; H05K 3/40; H05K 3/4007; H05K 4/4015
See application file for complete search history.

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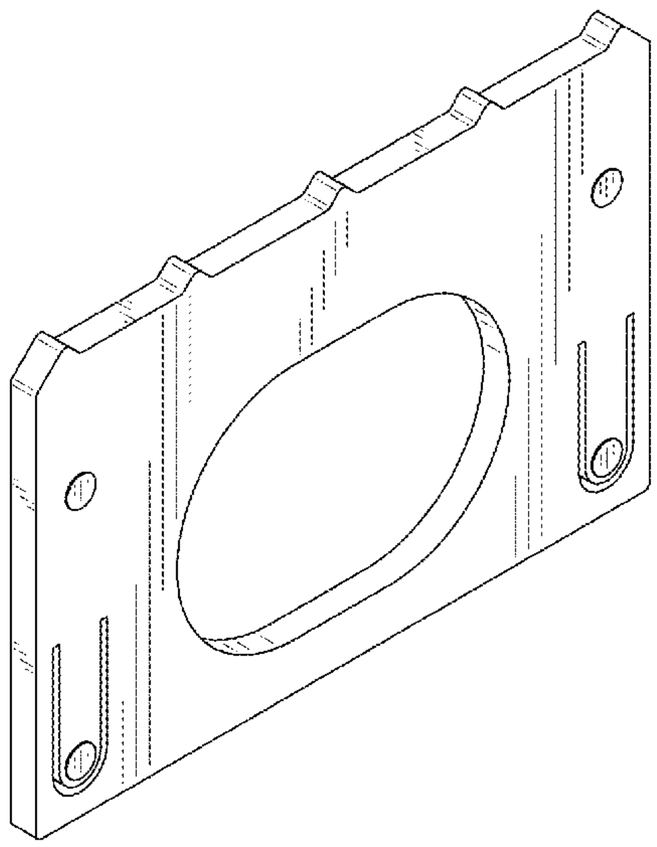
(57) **CLAIM**

The ornamental design for a compliant ground block and testing system for testing integrated circuits, as shown and described.

DESCRIPTION

FIG. **1** is a Top Perspective view of a compliant ground block and testing system for testing integrated circuits showing the new design;
FIG. **2** is a Bottom Perspective view thereof;
FIG. **3** is a Front view thereof;
FIG. **4** is a Back view thereof;
FIG. **5** is a Left view thereof;
FIG. **6** is a Right view thereof;
FIG. **7** is a Top view thereof; and,
FIG. **8** is a Bottom view thereof.

1 Claim, 5 Drawing Sheets



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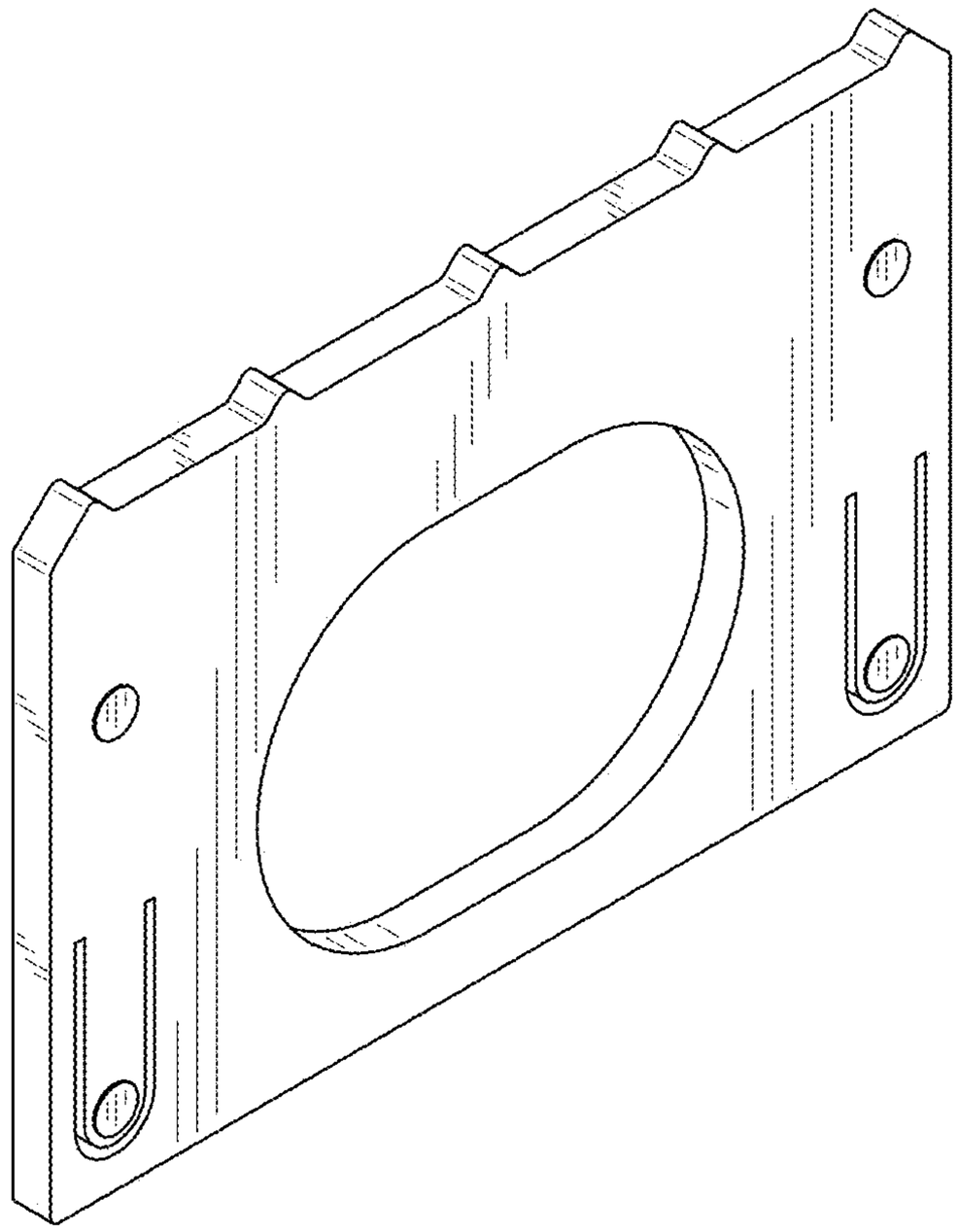

FIG. 1

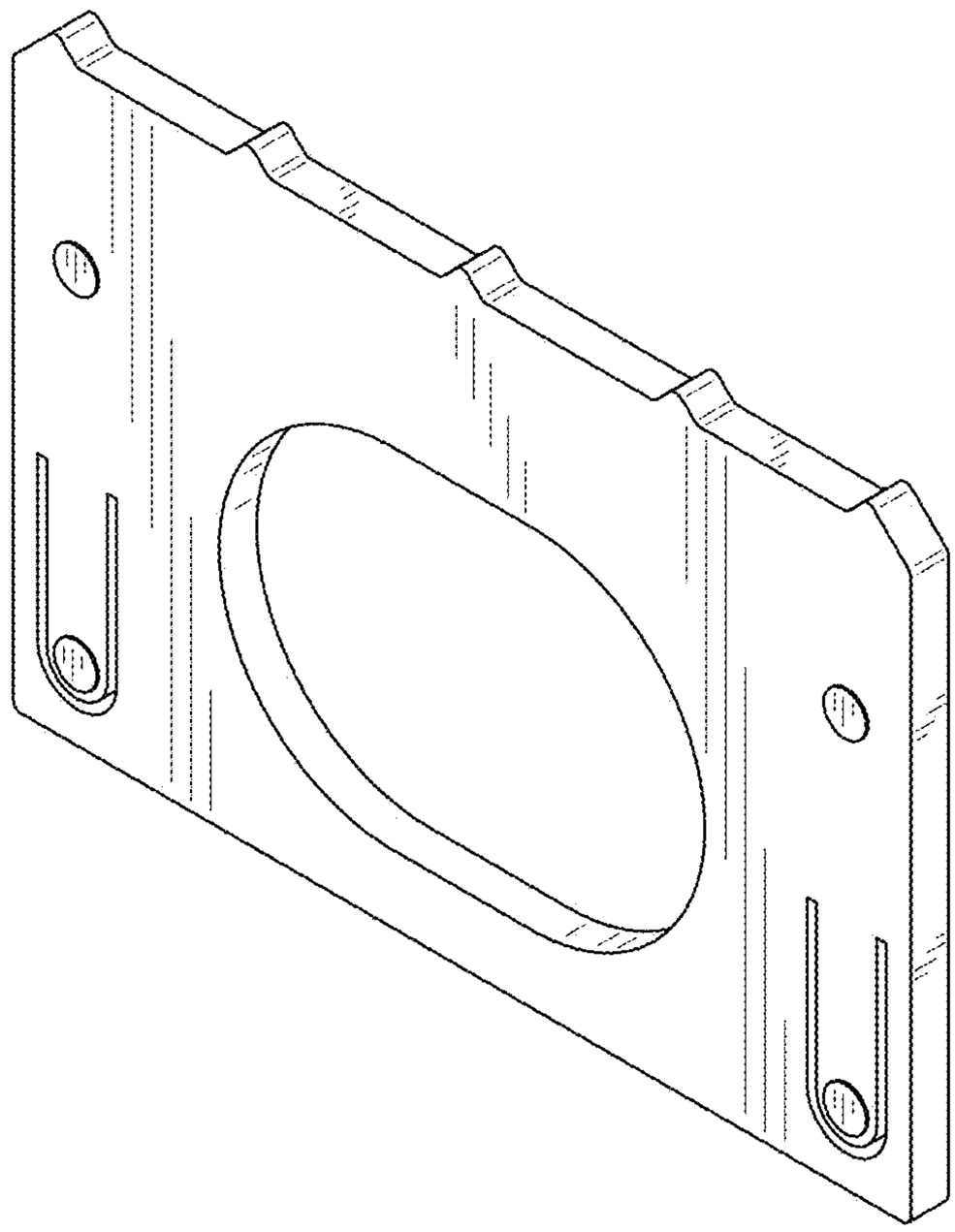

FIG. 2

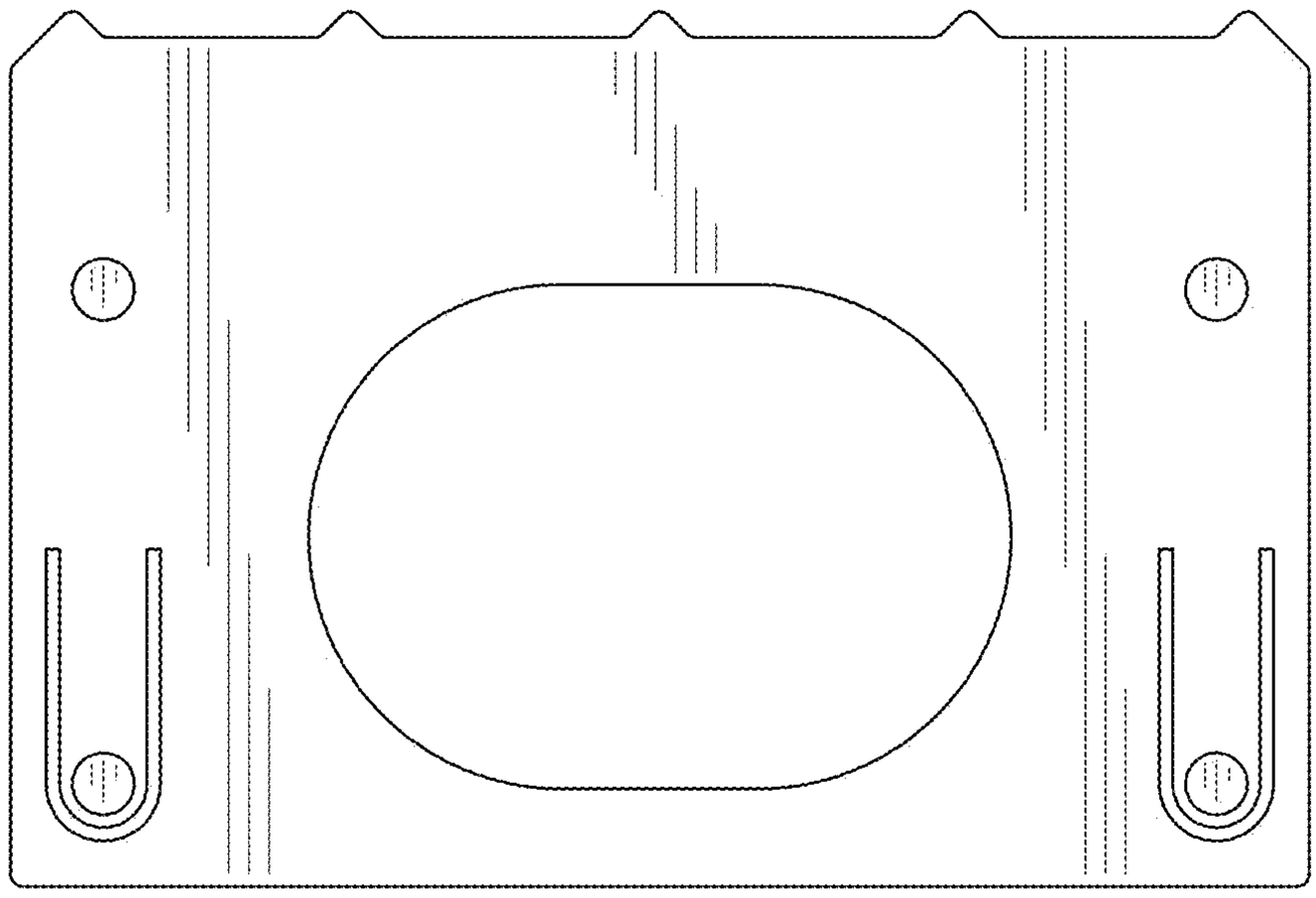

FIG. 3

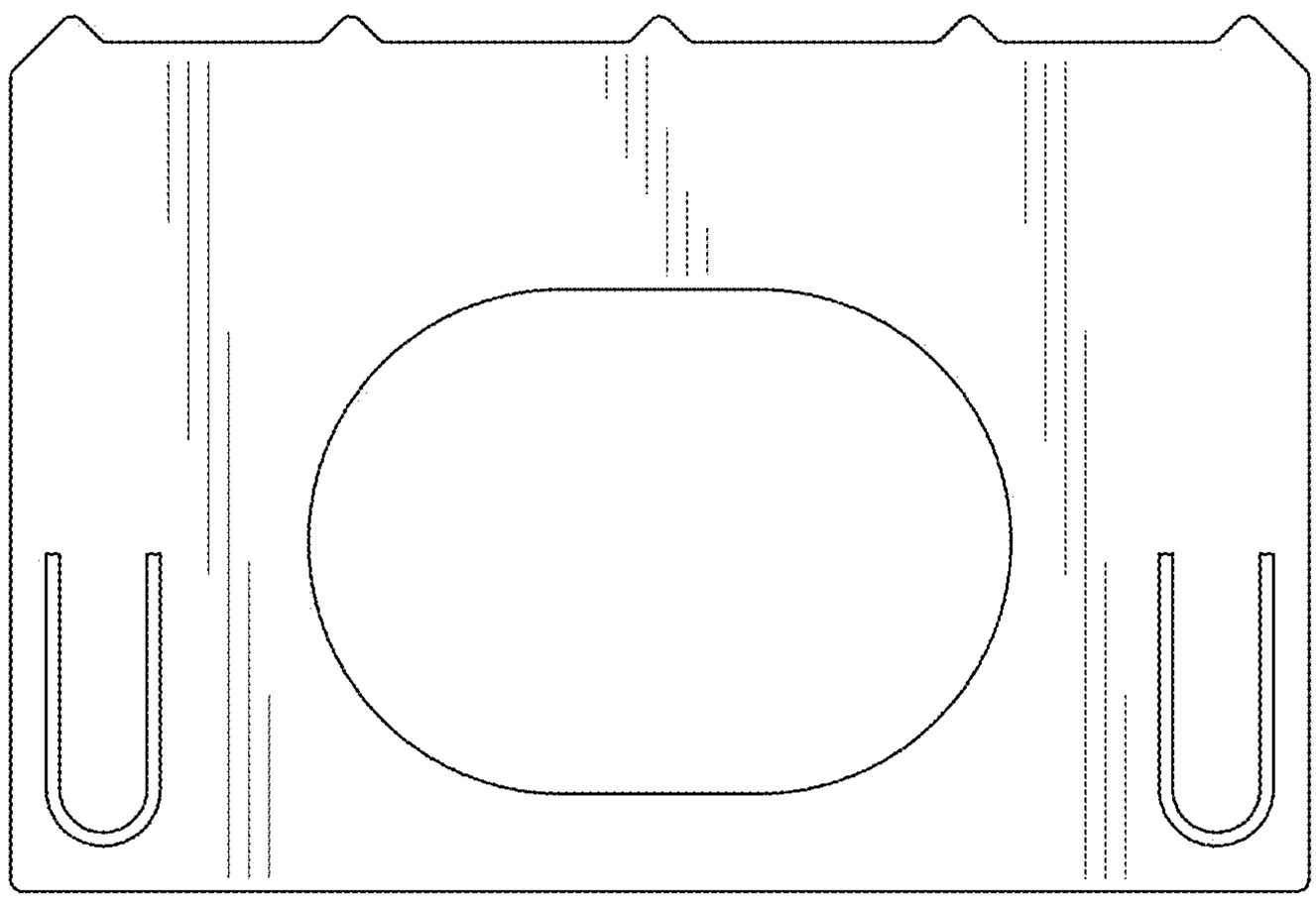

FIG. 4

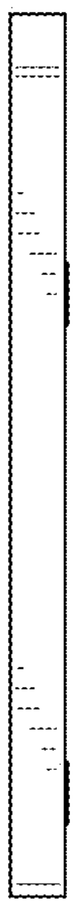

FIG. 5

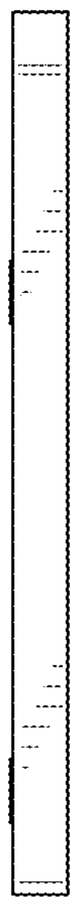

FIG. 6

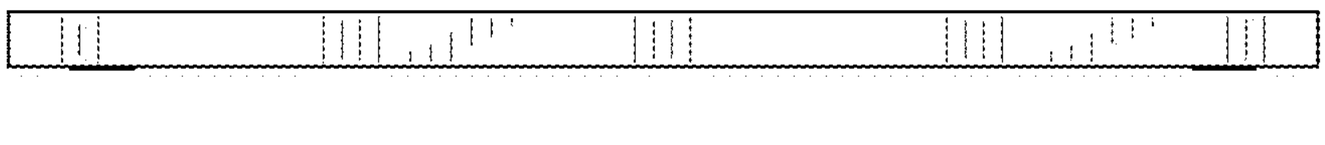

FIG. 7

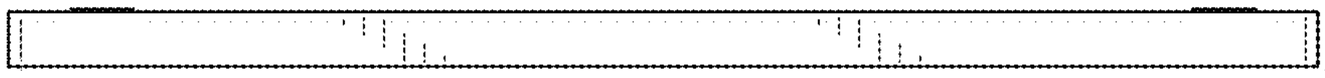

FIG. 8